

Synchrotron Radiation based transverse Emittance Diagnostics at Light Sources

Gero Kube

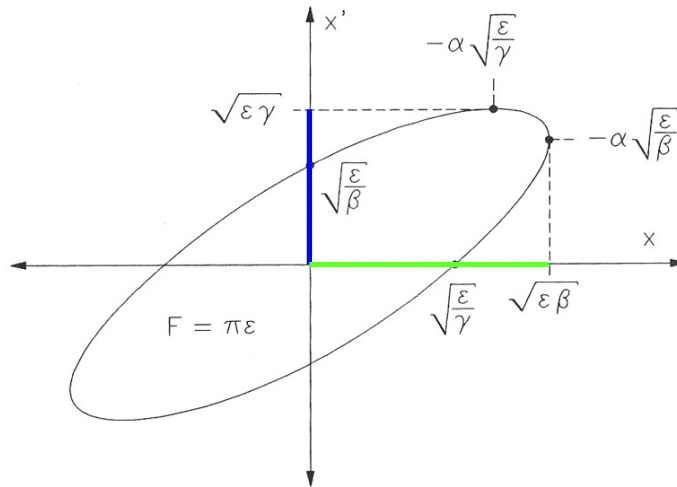
DESY / MDI

gero.kube@desy.de

- storage rings
- bending magnets
- standard systems

Beam Emittance

- projected area of transverse phase space volume
- emittance ε not directly accessible for beam diagnostics



- beam size

$$\sigma = \sqrt{\varepsilon \beta}$$

- beam divergence

$$\sigma' = \sqrt{\varepsilon \gamma}$$

- dispersion: $\sigma = \sqrt{\varepsilon \beta + (\eta \Delta p / p)^2}$ $\sigma' = \sqrt{\varepsilon \gamma + (\eta' \Delta p / p)^2}$

- influence of radiation properties σ_{rad}

- monitor resolution σ_{mon}

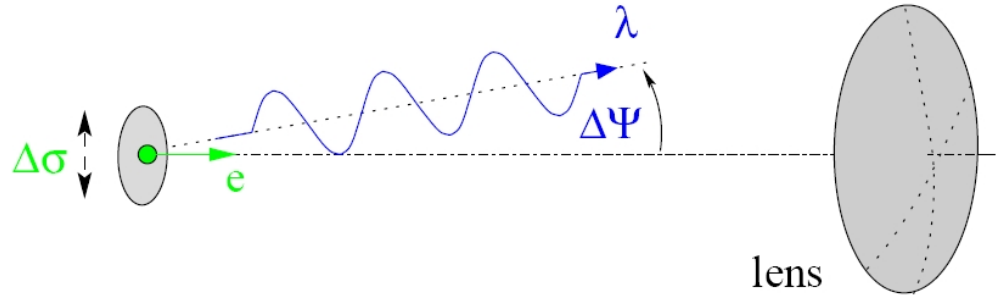
÷ photon beam spot σ_{ph} ÷ $\varepsilon(\beta, \gamma, \eta, \eta', \Delta p / p, \sigma_{\text{ph}}, \sigma_{\text{mon}}, \sigma_{\text{rad}})$

measure

calculate

Resolution Limits

- direct approach: imaging of beam profile



uncertainty principle:

$$\Delta\sigma \approx \frac{\lambda}{2\Delta\Psi}$$

- synchrotron radiation: small vertical emission angle $G \setminus$

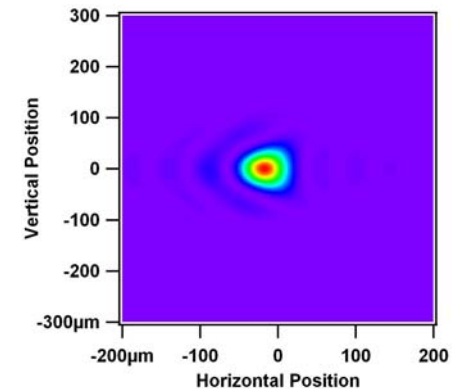
typical half opening angle ($\lambda \geq \lambda_c$) :

$$\Delta\Psi = \frac{1}{\gamma} \left(\frac{\lambda}{\lambda_c} \right)^{1/3}$$

÷ resolution fully limited by uncertainty principle

- example: HERA monitor

near field calculation of PSF including resolution broadening and depth of field at $\circ @ 500 \text{ nm}$



Resolution Improvements

ESRF: $E = 6 \text{ GeV}$, $\sigma_c = 0.35 \text{ nm}$
 $\circ @ 833 \text{ nm} \quad \div \quad \text{GeV}_v @ 593 \text{ pm}$
 $\oplus \text{V}_v @ 63 \text{ pm}$

uncertainty principle:

$$\Delta\sigma_v \approx \gamma \lambda^{2/3} \lambda_c^{1/3} / 2$$

1.) decrease of wavelength

\div VUV, soft X-ray, hard X-ray, ...

$\circ @ 31457 \text{ nm} \quad (10 \text{ keV photons}) \quad \div \quad \text{GeV}_v @ 4 \text{ pm}$

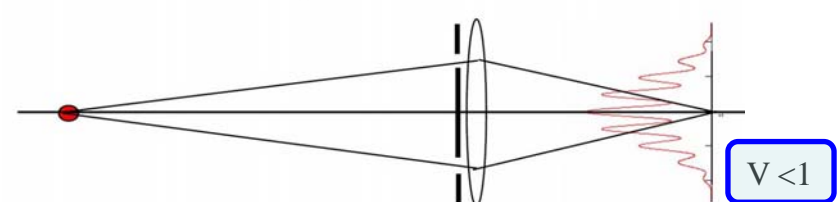
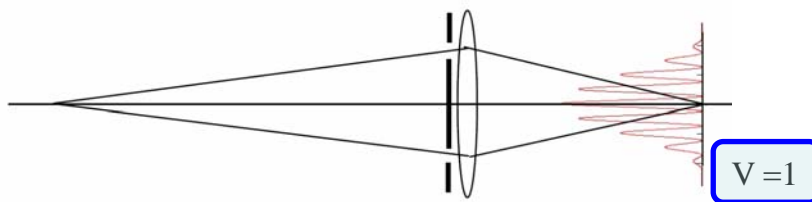
2.) interferometric approach

(T. Mitsuhashi, Proc. of PAC 1997, p.766)

visibility:

$$V = \frac{I_{\max} + I_{\min}}{I_{\max} - I_{\min}}$$

H. Fizeau, C.R.Acad.Sci. Paris 66 (1868) 934



Classification

O. Chubar: *Novel Applications of Optical Diagnostics*, Proc. EPAC 2000, p.117

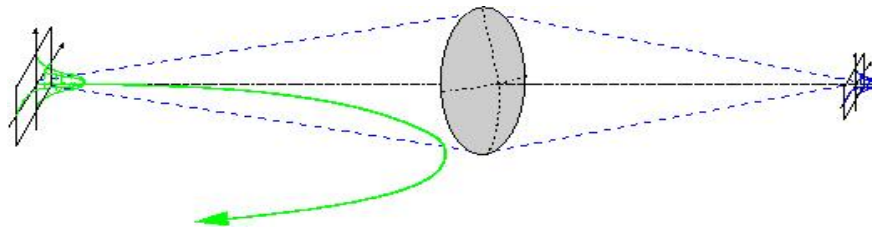
beam spot

wavefront manipulation

spatial resolving detector (CCD)

÷ signal :

imaging :

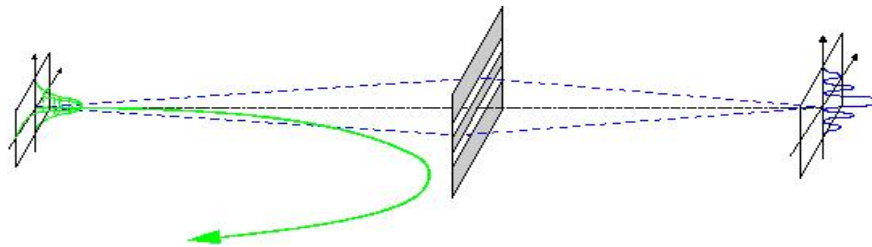


size of beam image

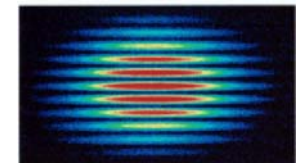


DORIS

interference :

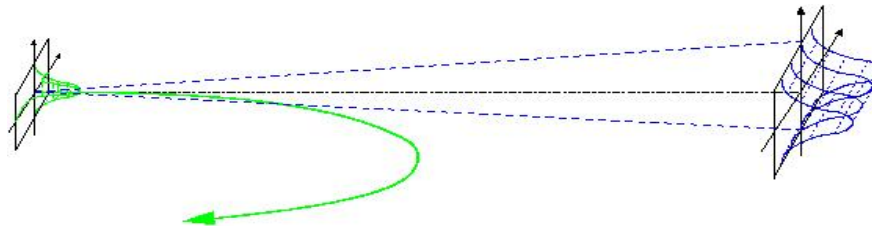


interference pattern (visibility)

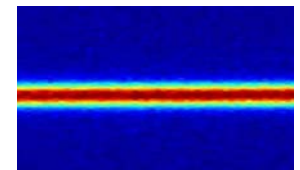


AURORA (courtesy T. Mitsuhashi)

projection :



angular distribution



ESRF (courtesy K. Scheidt)

Imaging: X-Ray Optics

complex index of refraction (X-rays):

$$n = 1 - g + i e$$

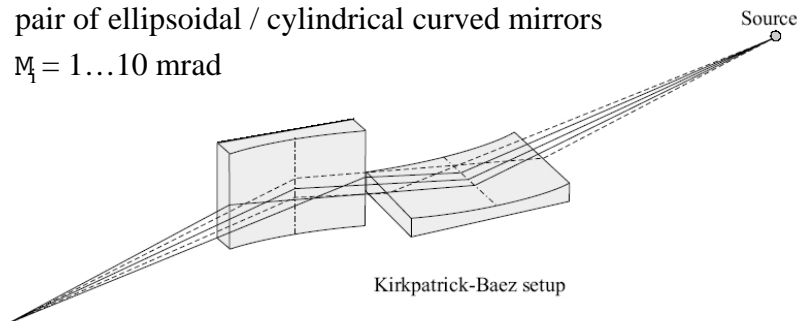
refractive index decrement g : $\delta \approx 10^{-6}$

- reflective optics
- diffractive optics
- refractive optics

Imaging: X-Ray Optics

- grazing incidence optics: Kirkpatrick-Baez mirrors

pair of ellipsoidal / cylindrical curved mirrors
 $M_1 = 1 \dots 10 \text{ mrad}$

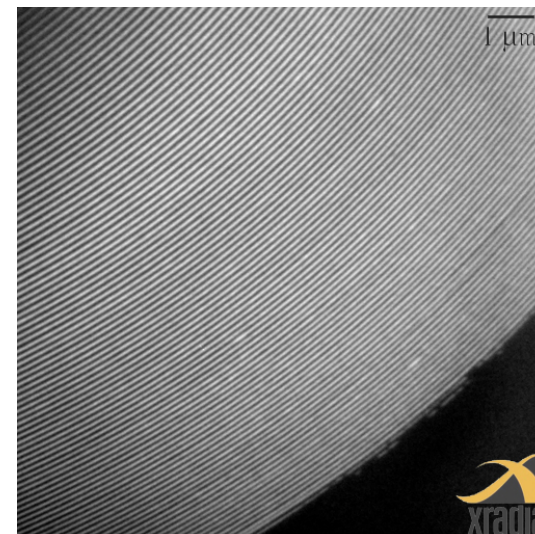
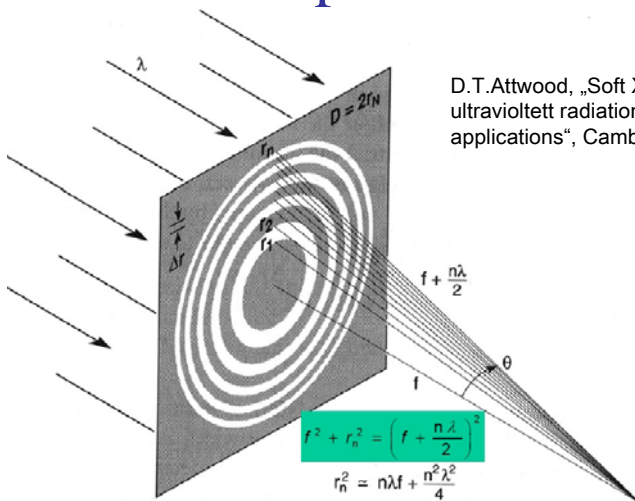


J. Tümmler: doctoral dissertation (2000), RWTH Aachen



Xradia: www.xradia.com

- Fresnel zone plates

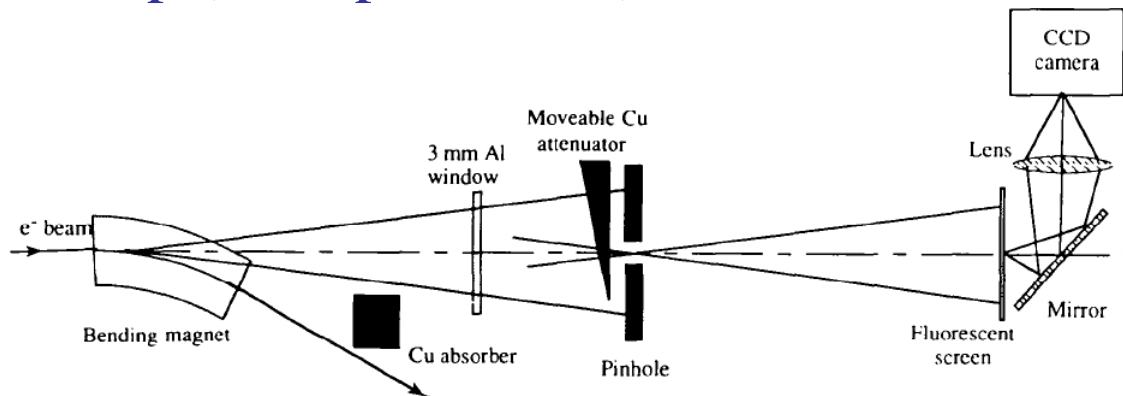


phase zone plate, Bragg Fresnel lens

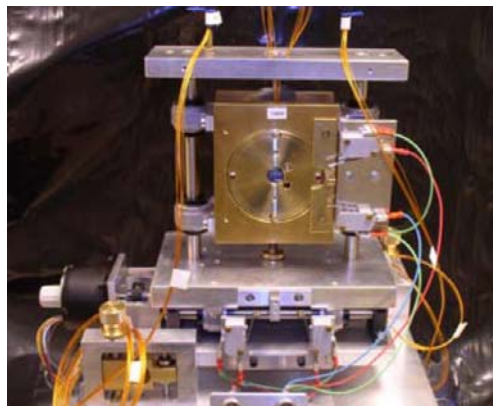
Imaging: X-ray Pinhole Camera

- „Camera Obscura“
description of phenomenon already by Aristoteles (384-322 b.C.) in „Problemata“
- Setup (example: ESRF)

P.Elleume, C.Fortgang, C.Penel and E.Tarazona, J.Synchrotron Rad. 2 (1995) , 209



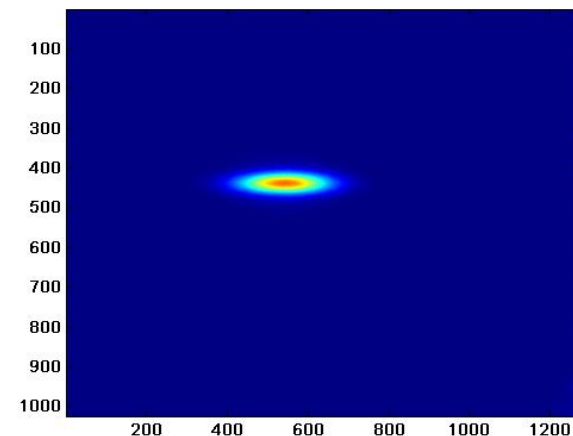
ID-25 X-ray
pinhole camera:



pinhole setup
@ DORIS

resolution:

$$\sigma_{res} \approx 20 \mu m$$



courtesy of K.Scheidt, ESRF

Imaging: Compound Refractive Lens

lens-maker formula:

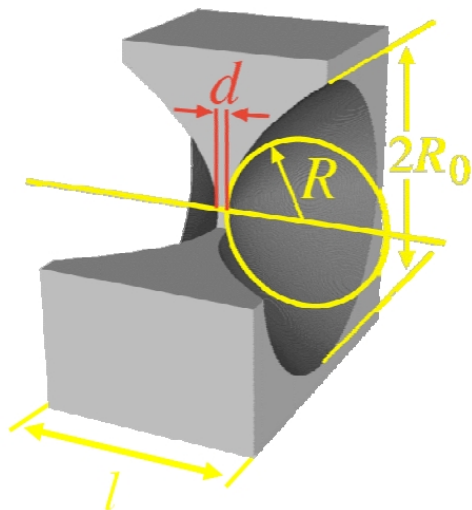
$$1/f = 2(n-1) / R$$

X-ray refraction index :

$$n = 1 - \delta + i\beta, \quad \delta \approx 10^{-6}$$

➤ concave lens shape

➤ strong surface bending R

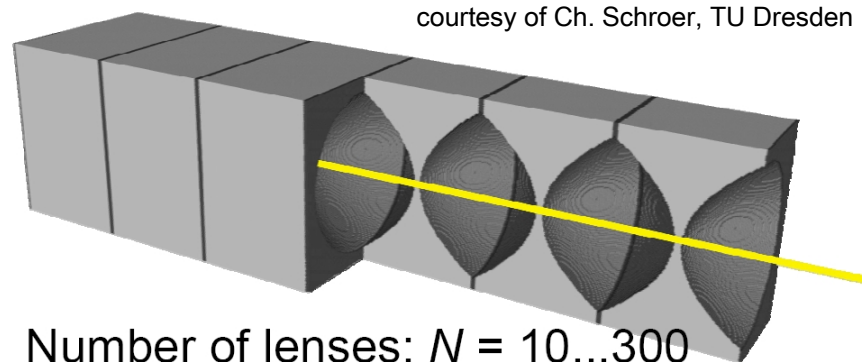


➤ small Z (Be, Al, ...)

➤ small d

$$f = \frac{R}{2\delta N}$$

÷ many lenses



courtesy of Ch. Schroer, TU Dresden

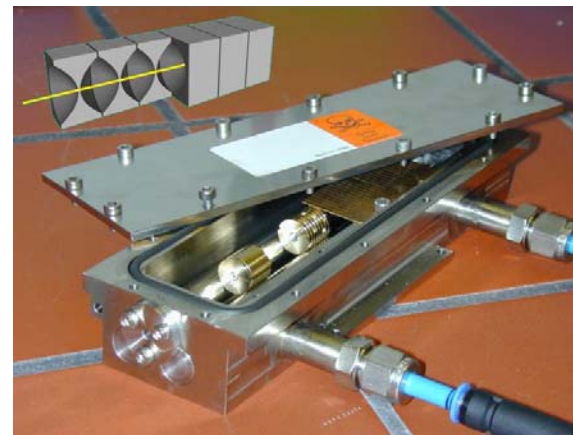
Number of lenses: $N = 10 \dots 300$

PETRA III @ 15 keV:

- $R = 201.8 \text{ pm}$, $R_0 = 447 \text{ pm}$, $d = 10 \text{ pm}$
- $N = 20$
- material: beryllium

$$f = 3.33 \text{ m}$$

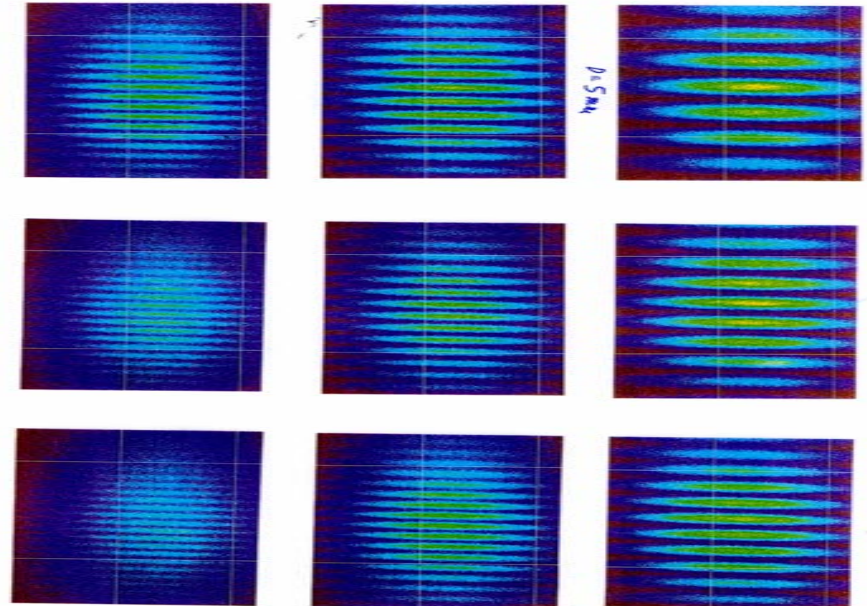
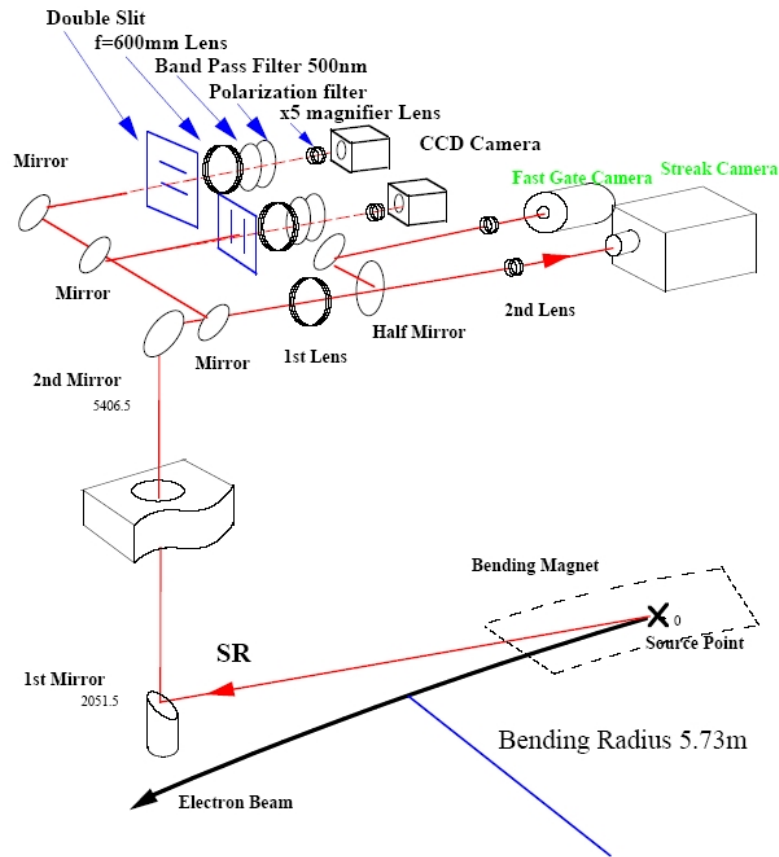
$$\sigma_{res} \approx 1 \mu\text{m}$$



www.xray-lens.de

Interference: ATF (KEK)

vertical beam size:

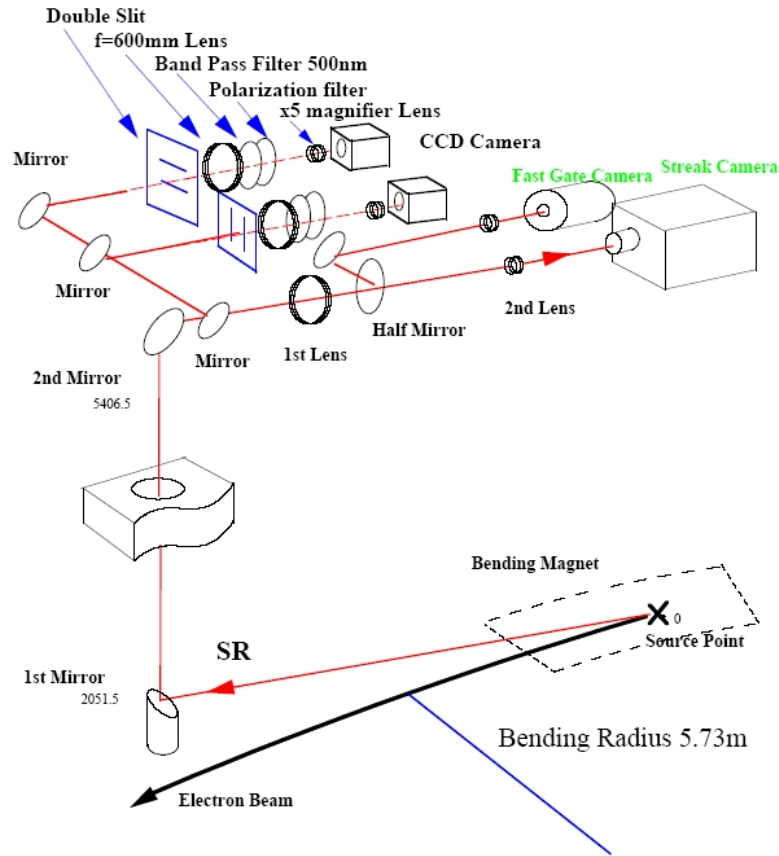


H.Hanyo et al., Proc. of PAC99 (1999), 2143

courtesy of T.Mitsuhashi, KEK

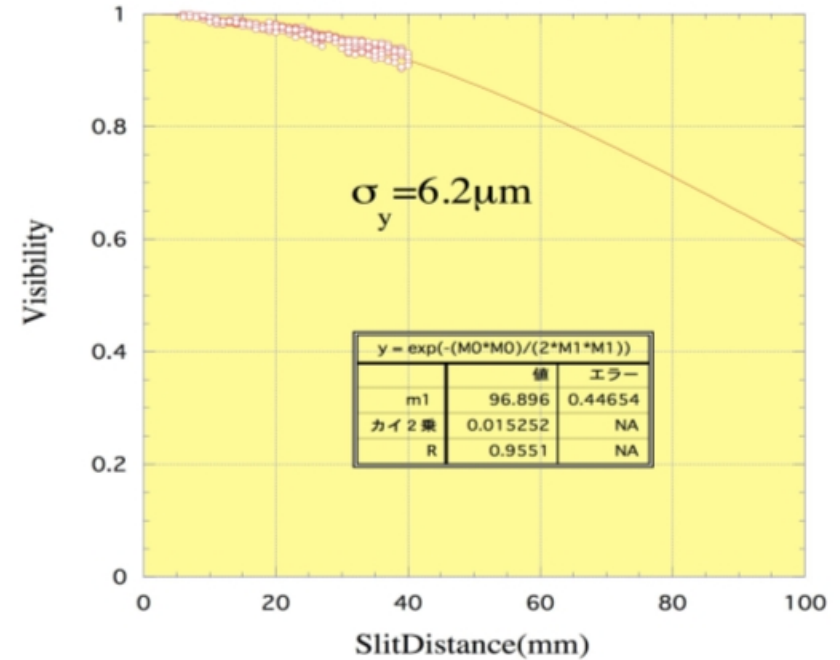
- smallest result: 4.7 pm with 400nm @ ATF, KEK
accuracy ~ 1 pm

Interference: ATF (KEK)



vertical beam size:

ATF-Damping Ring Vertical Beam Size Measurement



courtesy of T.Mitsubishi, KEK

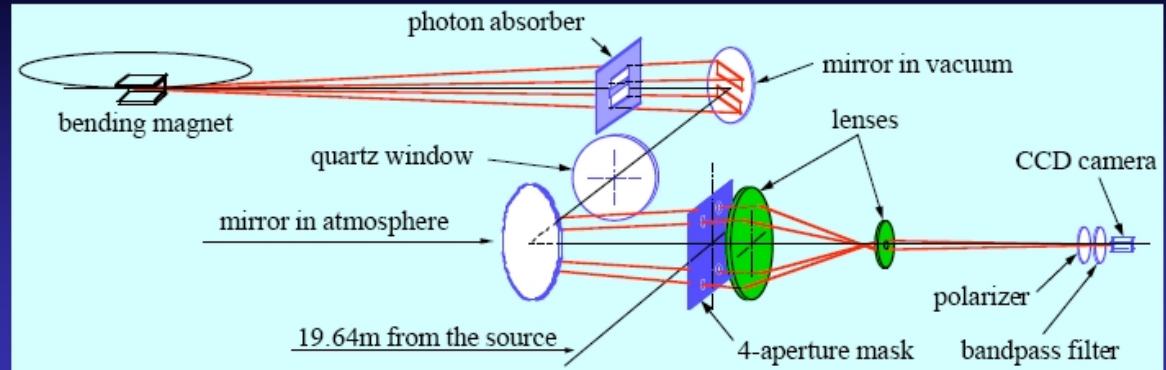
H.Hanyo et al., Proc. of PAC99 (1999), 2143

- smallest result: 4.7 pm with 400nm @ ATF, KEK
accuracy ~ 1 pm

Interference: 2D Interferometer

SPRING-8 2D Synchrotron Light Interferometer

M. Masaki & S. Takano,
 J. Sync. Rad. (2003). 10, p295



Resolution

$$\sigma_{inter,X} = 121\mu\text{m}, \quad \sigma_{inter,Y} = 52\mu\text{m}$$

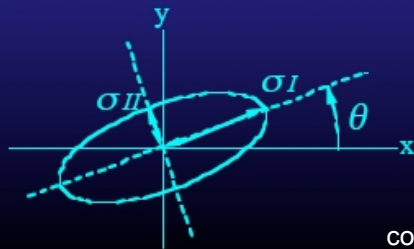
2D Beam Profiling

model function:
$$\tilde{I}(x,y) = \int_{-\infty}^{\infty} I(x,y;x_e,y_e) \rho(x_e,y_e) dx_e dy_e$$

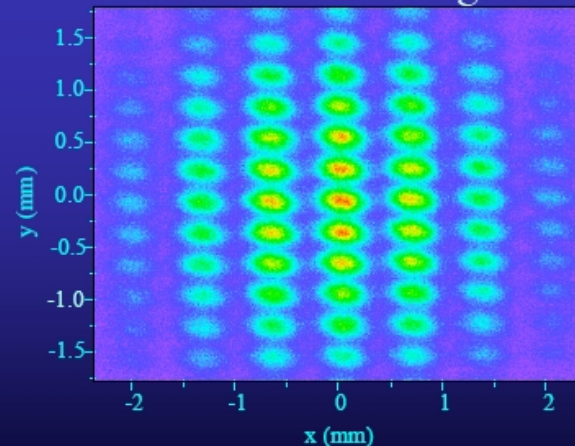
point-spread function: $I(x,y;x_e,y_e)$

electron beam : $\rho(x_e,y_e)$

elliptical Gaussian distribution



Observed interferogram



$$\sigma_I = 116(\mu\text{m}), \quad \sigma_{II} = 64(\mu\text{m}), \quad \theta = -18(\text{deg.})$$

courtesy of S.Takano, Spring-8

Projection: In Air X-Ray Detectors

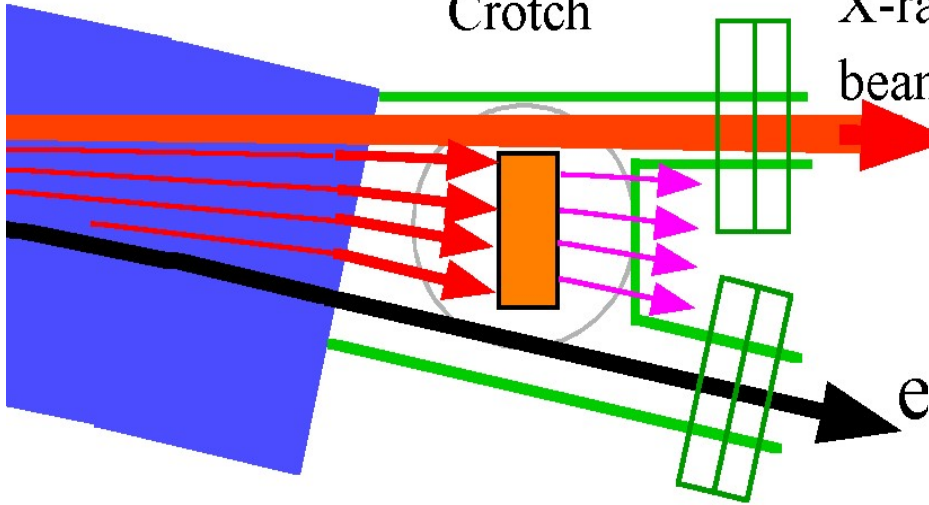


= 155W/mrad

40mm Cu & 5mm Fe

Crotch

X-rays
beamline

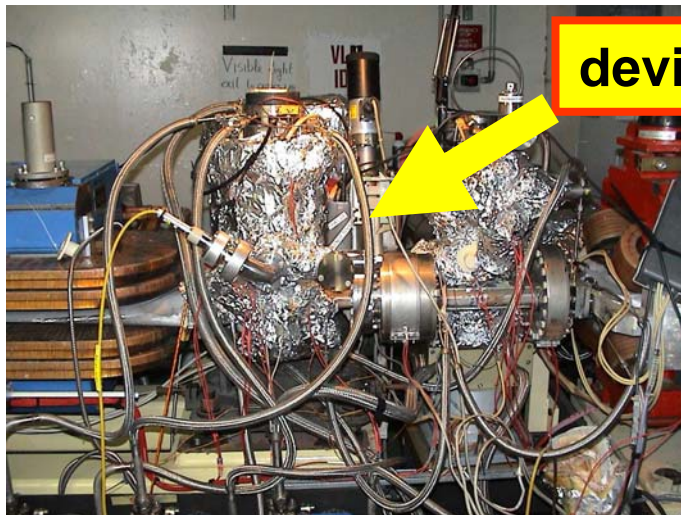
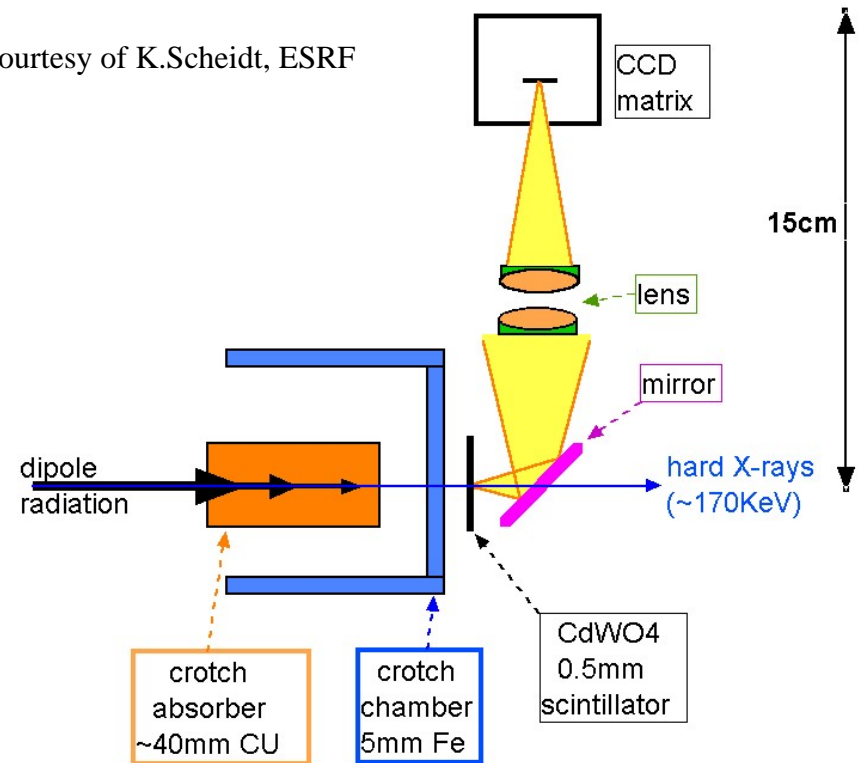


K.Scheidt, Proc. of DIPAC05 (2005), 238

K.Scheidt, Proc. of BIW06 (2006), to be published

side-view i.e. in the vertical plane of the beam:

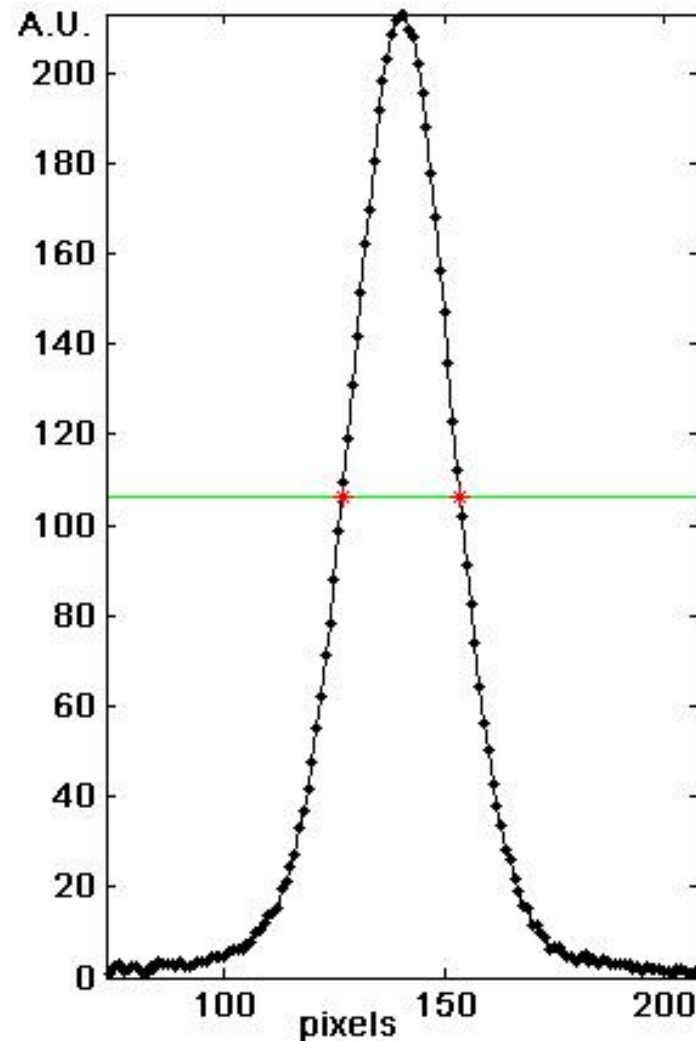
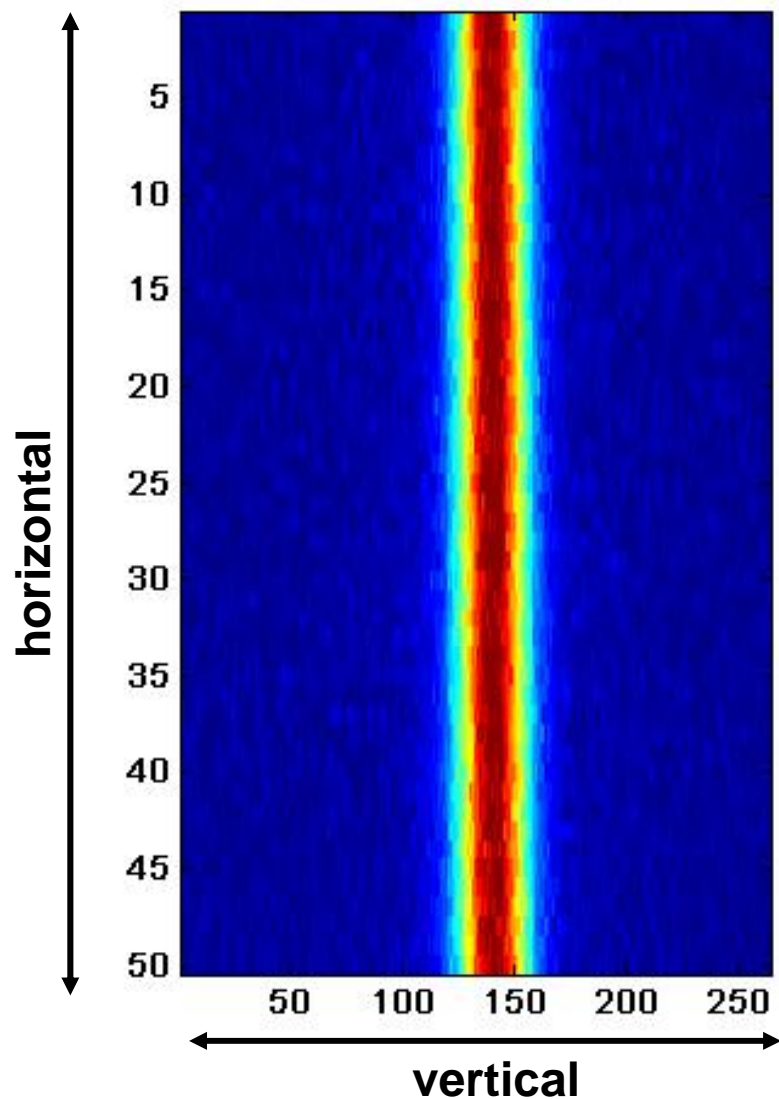
courtesy of K.Scheidt, ESRF



device

Projection: In Air X-ray Detectors

size [fwhm um] = 118.85



courtesy of K.Scheidt, ESRF

Summary

	Energy [GeV]	$h_x \ 2h_y \ \hat{s} \ \text{nm rad}$	$v_x \ 2v_y \ \hat{\mu}\text{m}$	$G \pm v_x \ 2v_y \ \hat{\mu}\text{m}$	Type	Reference
Spring-8	8	3.4 / 0.01	114 / 14	121 / 52 ~ 4	2-dim interferometry zone plate + monochr.	DIPAC 01/J.Sync.Rad (03) DIPAC 01+05/ NIM A556
APC	7	2.5 / 0.03	140 / 55	35 / 35	pinhole camera	EPAC 98
ESRF	6	3.9 / 0.03 (0.01)	104 / 33 - / 35	60 / 40	pinhole camera in air X-ray detector	J.Sync.Rad (95) DIPAC 05/BIW (06)
DIAMOND	3	2.7 / 0.03	50 / 25	25 / 25	pinhole camera	BIW 04/DIPAC 05
SOLEIL	2.75	3.75 / 0.04	114 / 14	121 / 52	pinhole camera	DIPAC 03
ALBA	3	4 / 0.04	45 / 35	20 / 20	pinhole camera	private communication
ELETTRA	2	7 / 0.07			opt. imaging + interferometry	EPAC 00
	2.4	9.7 / 0.1	146 / 25	30 / 30		
SLS	2.4	4.8 / 0.05	45 / 40	2 / 2	imaging (zone plate) (pinhole array ?)	DIPAC 01
NSLS	2.58	90 / 0.1		16 / 16	pinhole camera	EPAC 96
PF KEK	2.5	37 / 0.37	262 / 87	~ 1	interferometry	PAC 99
ALS	1.9	6 / 0.03	88 / 45	10 / 10	Kirkpatrick-Baez	BIW 96
MAX-II	1.5	9 / 0.09	~100 / ~ 20	2 / 2	opt. imaging + interferometry	EPAC 04
BESSY-II	1.9	6 / < 0.02	50-60 / 40-50	11 / 11 3 / 3	pinhole array + Bragg-Fresnel lens	NIM A467/468 (2001)